

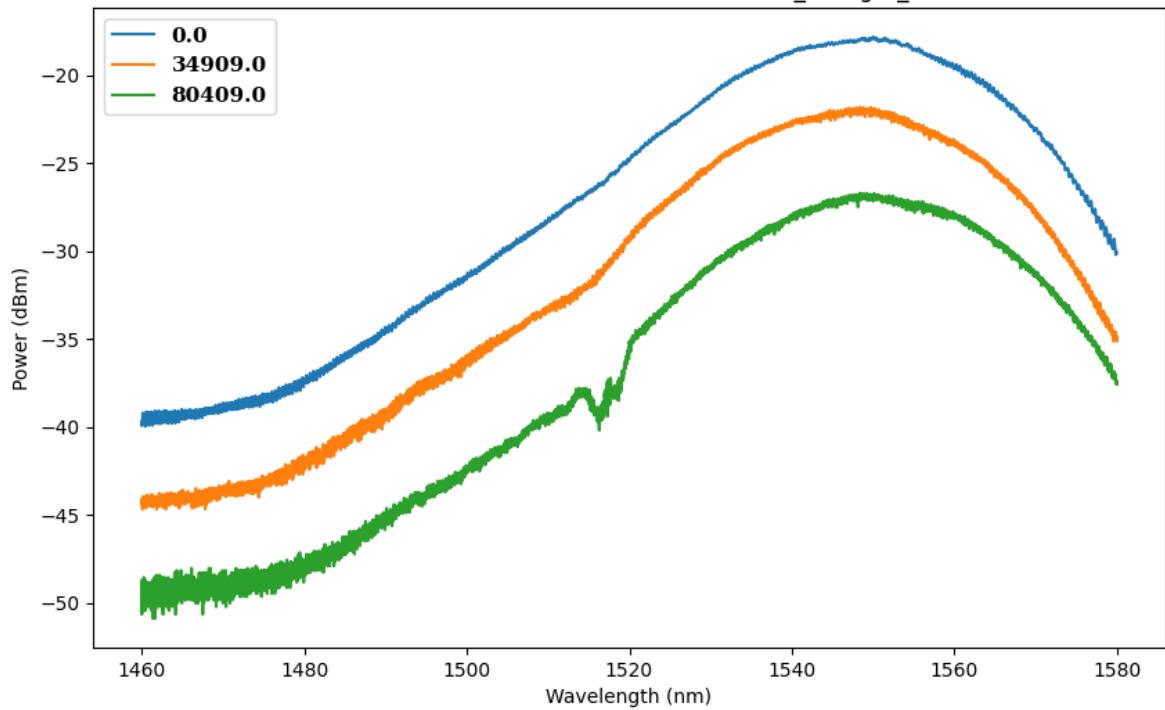
# Analysis Report of EdX\_May\_2023\_1550TE chip

Measurement date: 2023-08-28

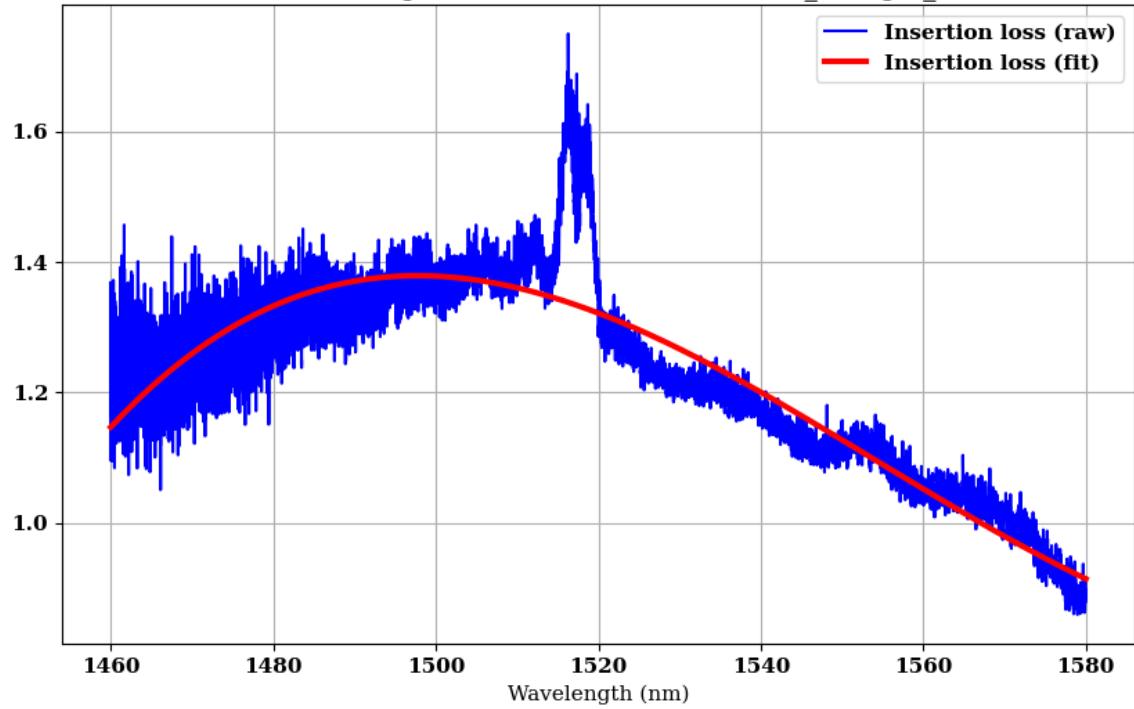
Process: ANT

Name	Wavelength	Polarization	Data	Error	Analysis
PCM_Straight	1550nm	TE	1.13	0.0	Insertion Loss (dB/cm)
PCM_Spiral	1550nm	TE	4.34	0.65	Insertion Loss (dB/cm)
PCM_SWG	1550nm	TE	1.56	0.22	Insertion Loss (dB/cm)
PCM_YBranch	1550nm	TE	0.17	0.03	Insertion Loss (dB/device)
PCM_ContraDC	1550nm	TE	0.09	0.03	Insertion Loss (dB/device)
PCM_Bragg_Period	1550nm	TE	-4.72	N/A	Bragg Drift (nm)
PCM_Bragg_dW	1550nm	TE	N/A	N/A	Bragg Drift (nm)
PCM_GIndex	1550nm	TE	4.15	0.09	Group Index

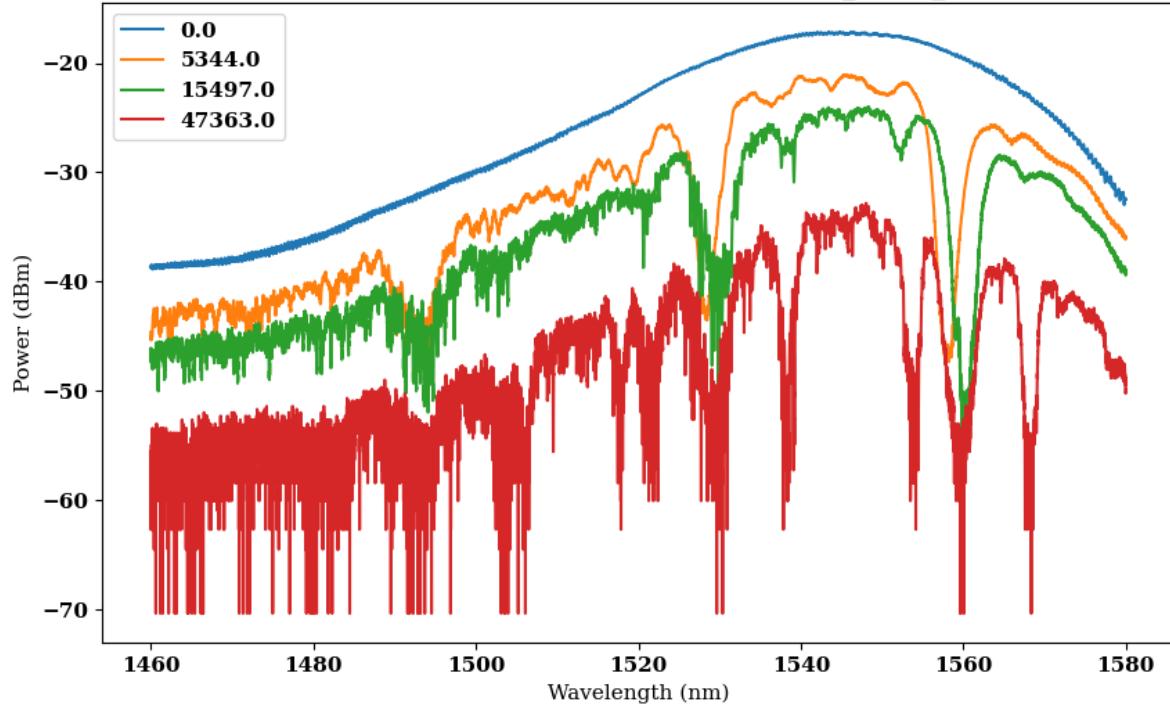
Raw Measurement of Cutback Structures for PCM\_Straight\_TE1550nm



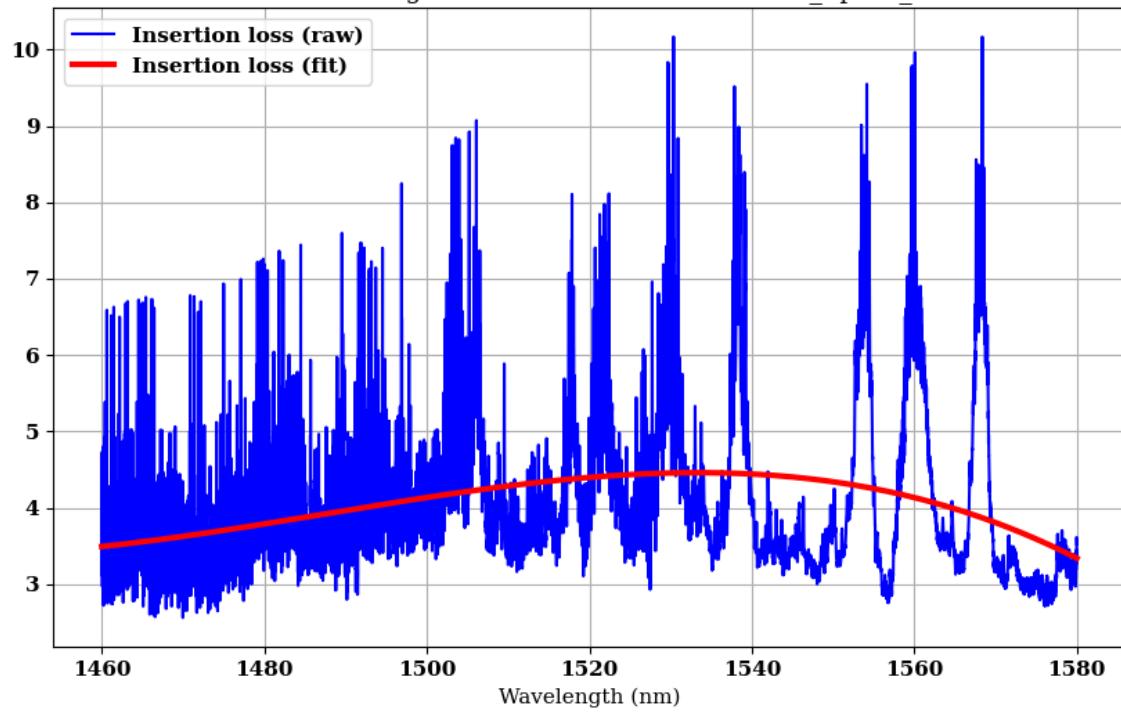
Insertion Losses Using the Cutback Method for PCM\_Straight\_TE1550nm



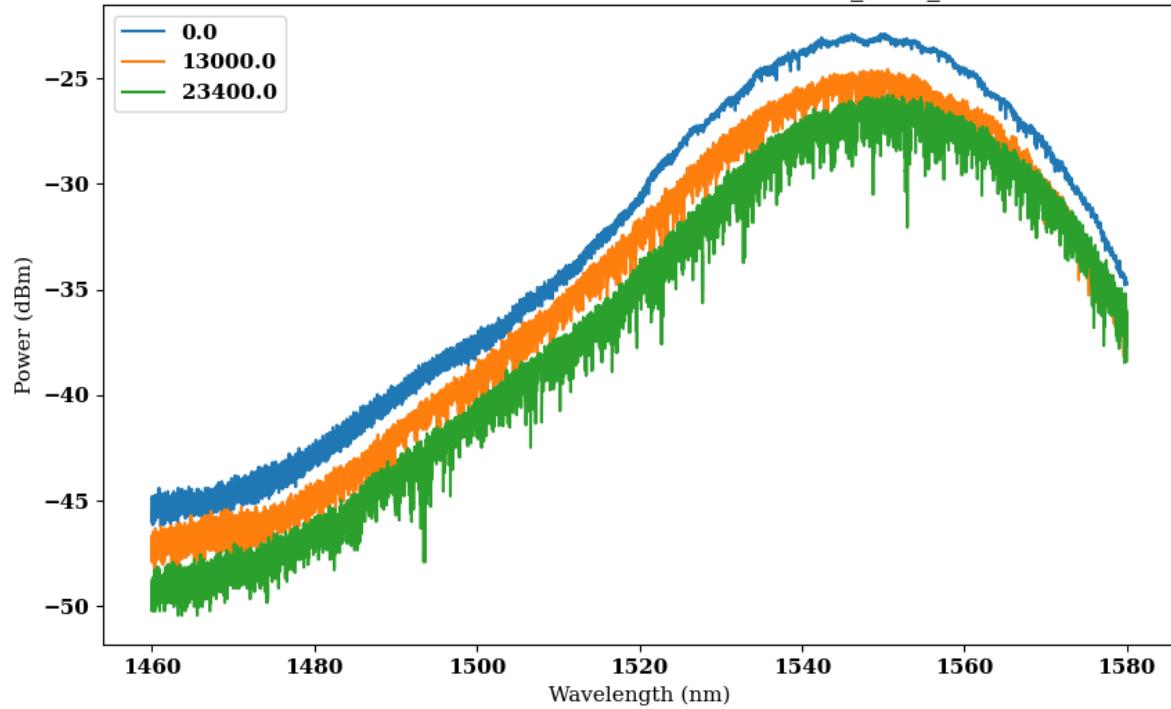
Raw Measurement of Cutback Structures for PCM\_Spiral\_TE1550nm



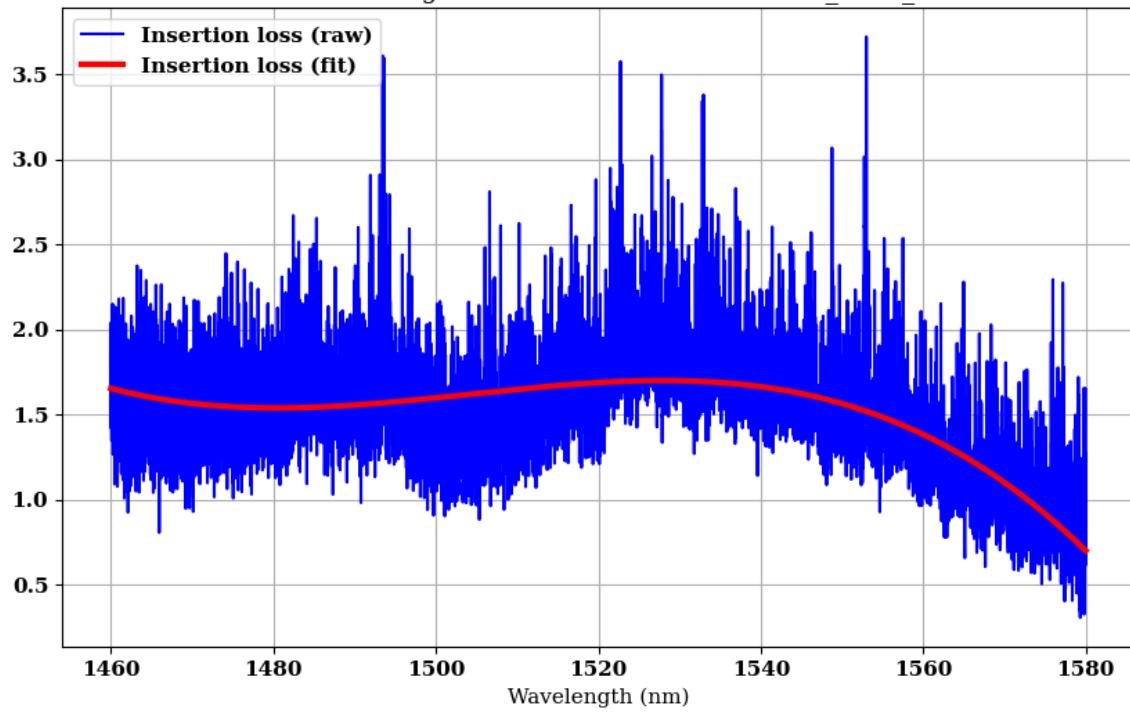
Insertion Losses Using the Cutback Method for PCM\_Spiral\_TE1550nm

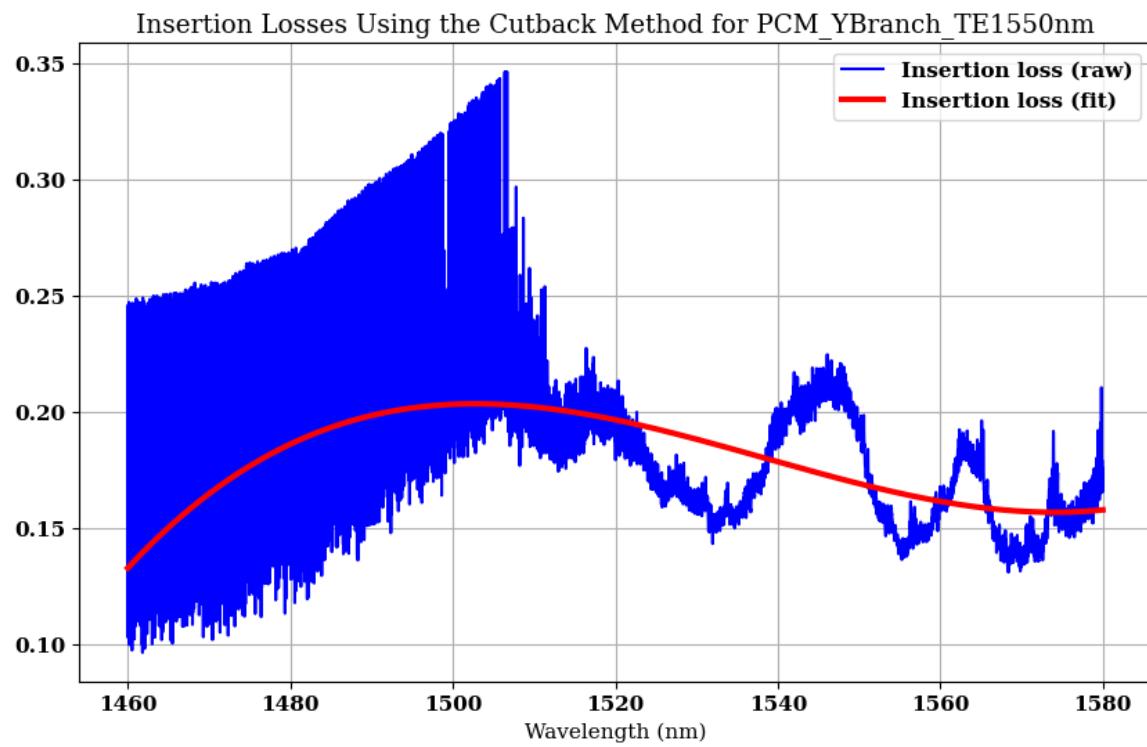
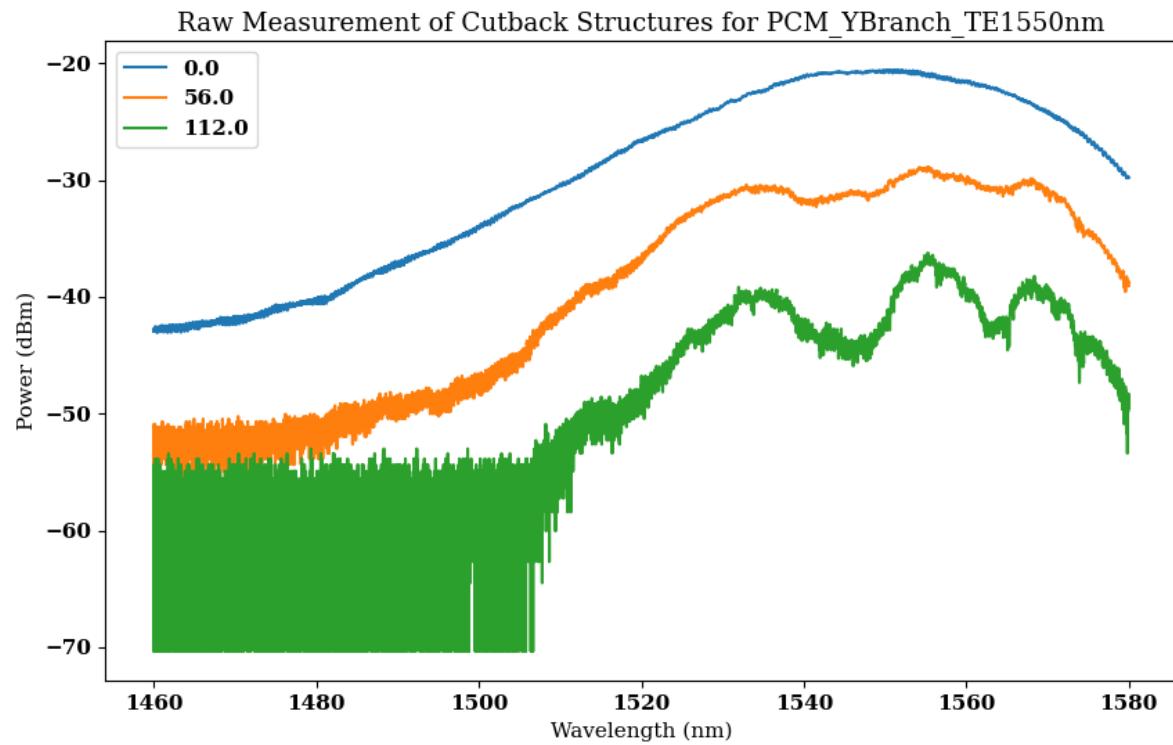


Raw Measurement of Cutback Structures for PCM\_SWG\_TE1550nm

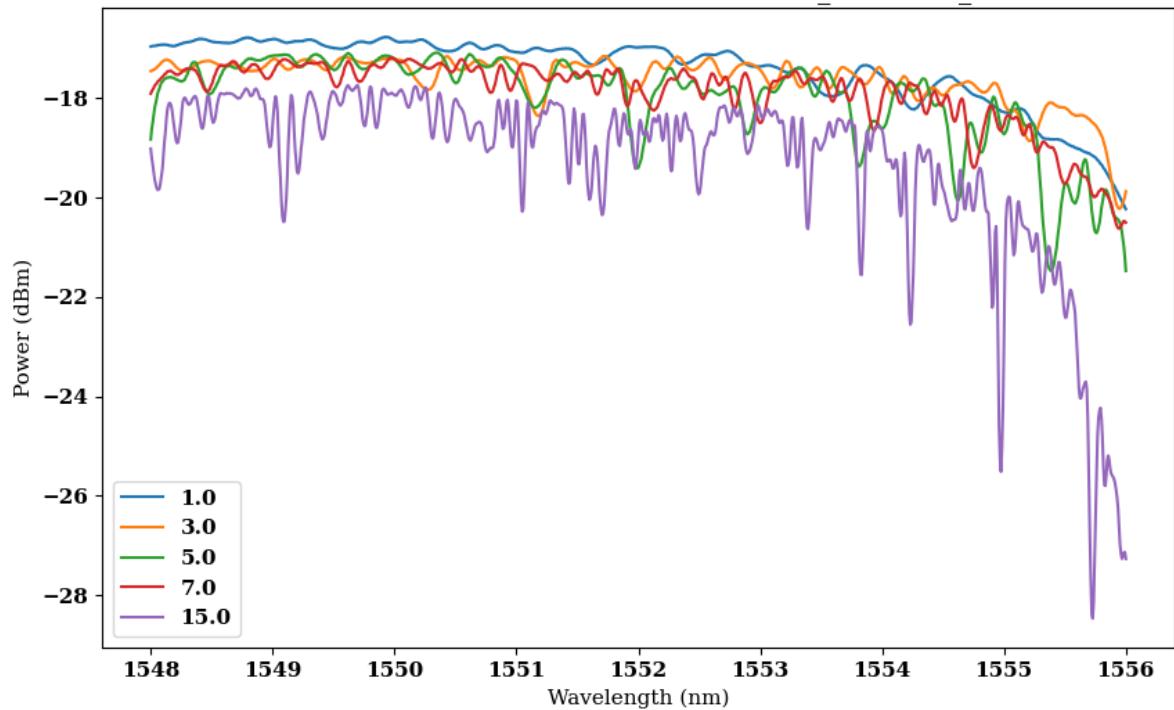


Insertion Losses Using the Cutback Method for PCM\_SWG\_TE1550nm

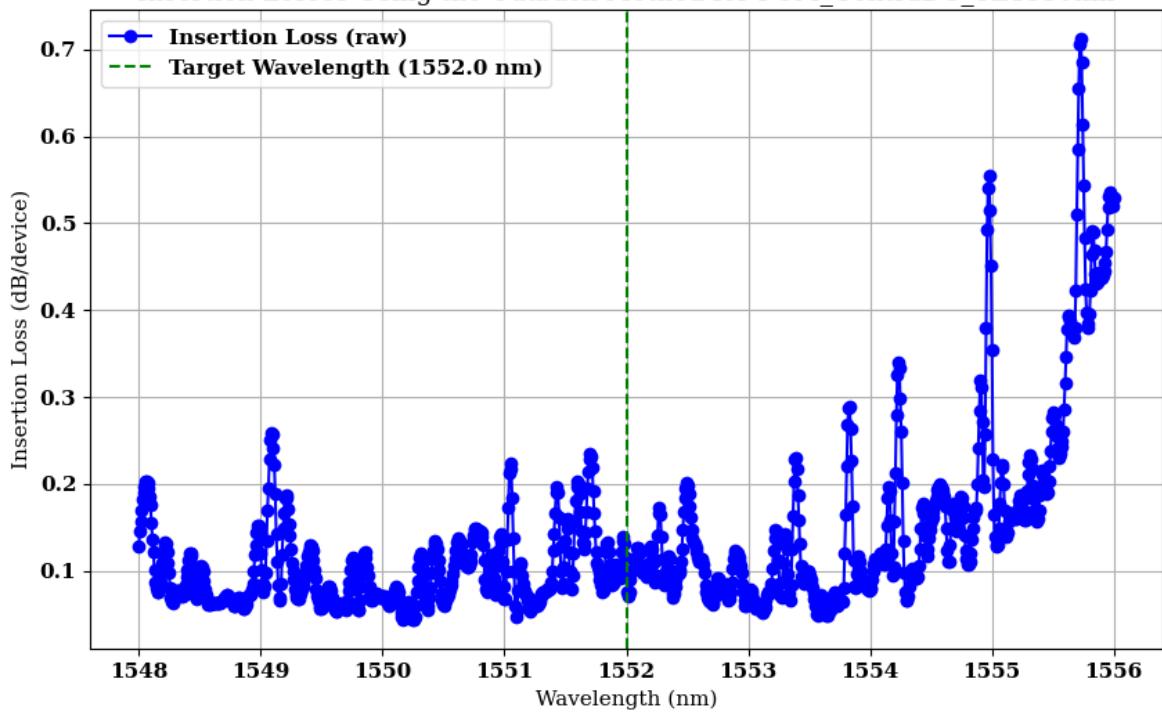




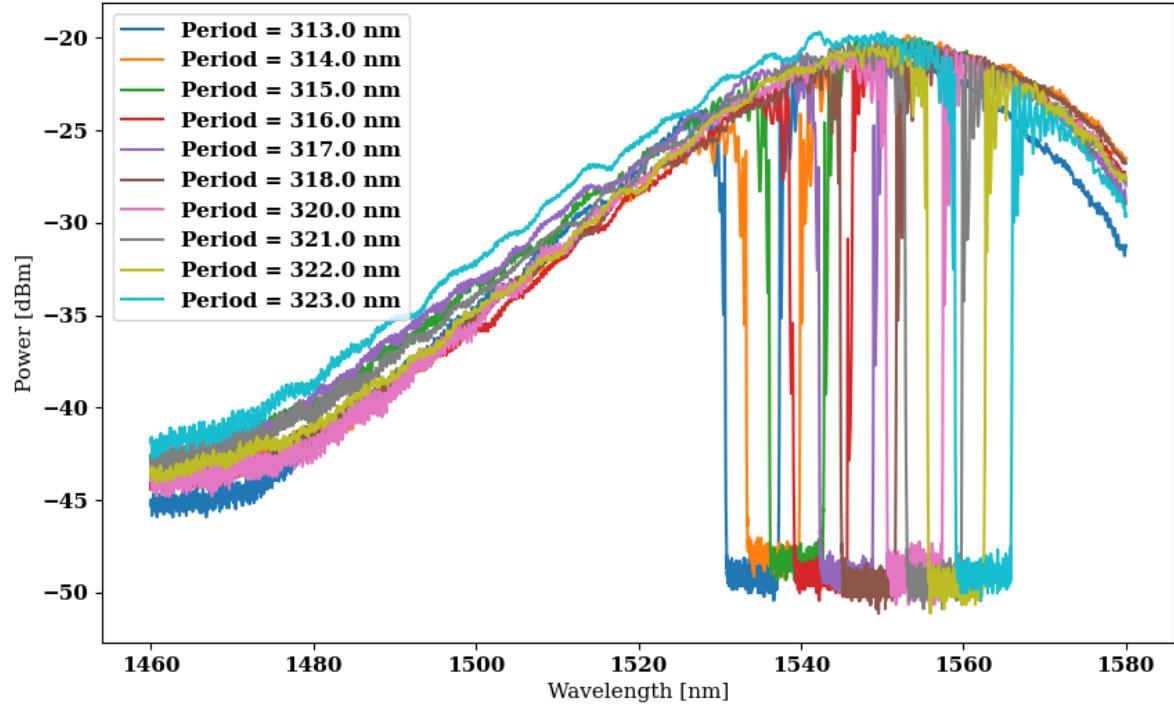
Raw Measurement of Cutback Structures for PCM\_ContraDC\_TE1550nm



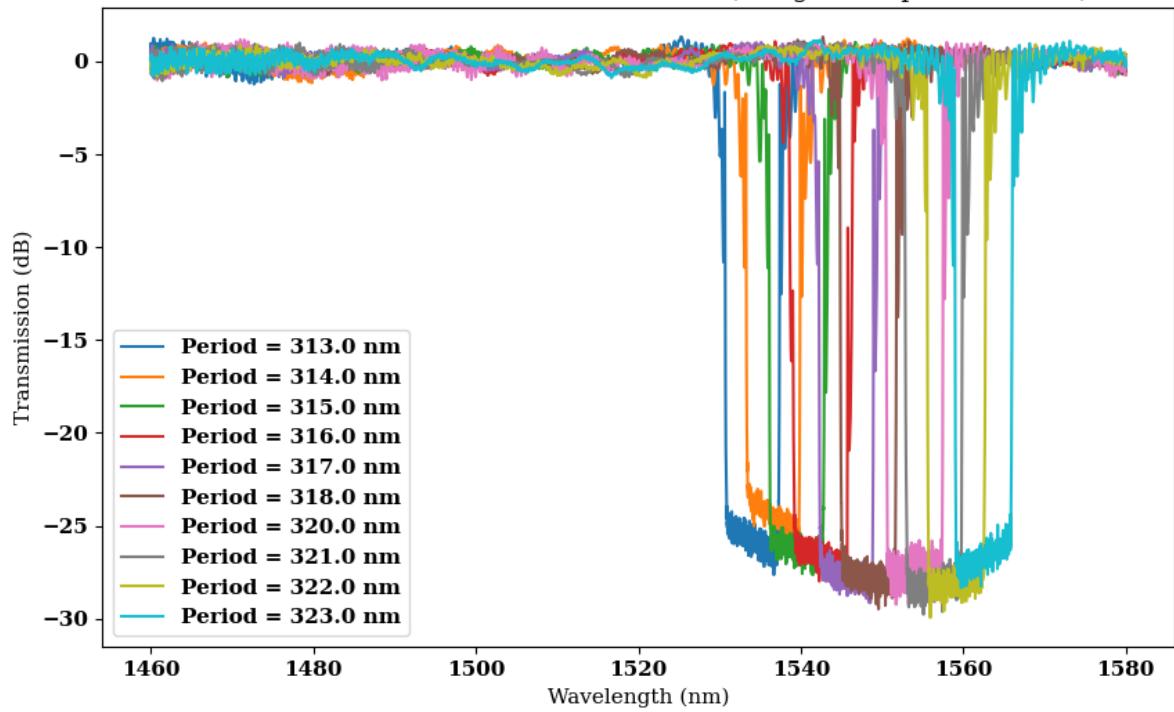
Insertion Losses Using the Cutback Method for PCM\_ContraDC\_TE1550nm



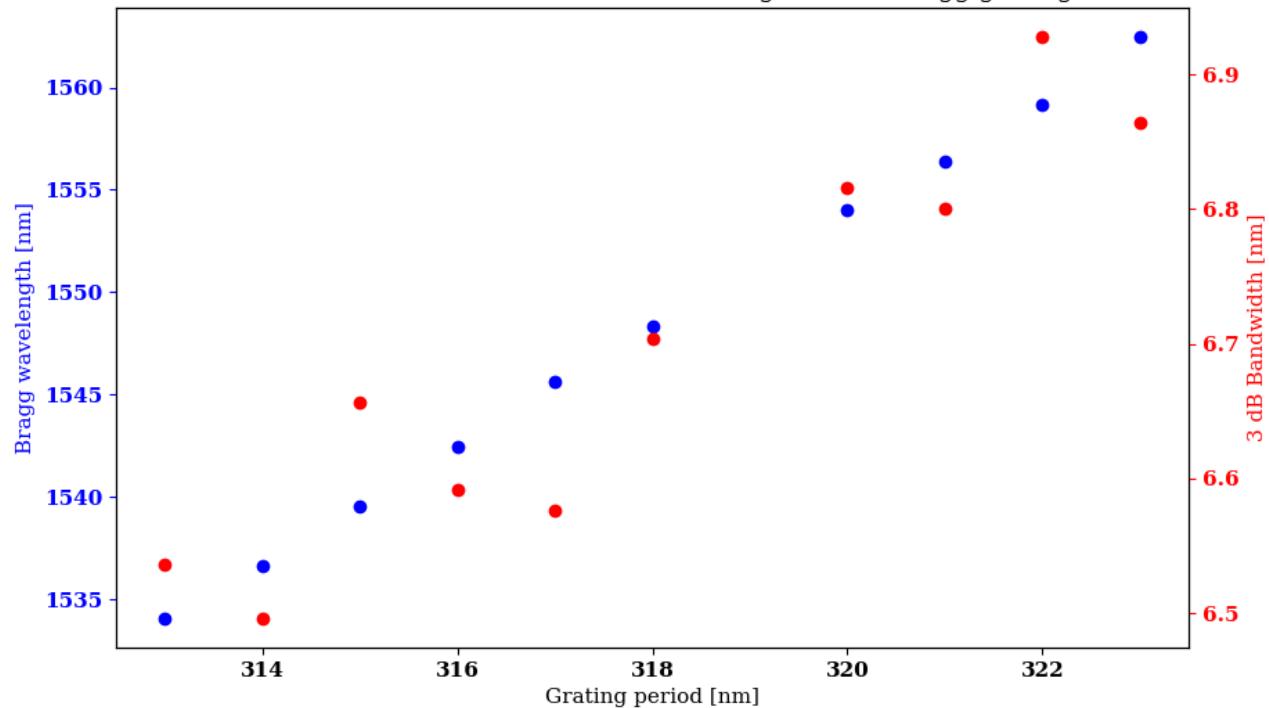
Raw measurement of all structures



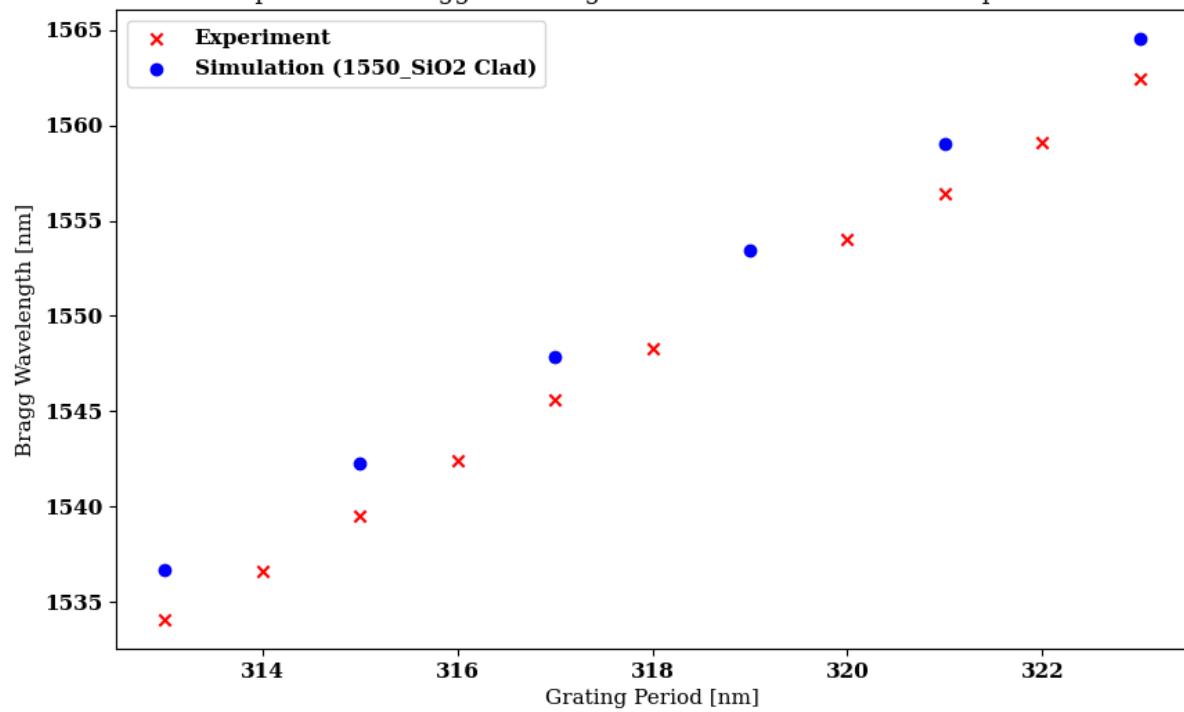
Calibrated measurement of all structures (using envelope calibration)



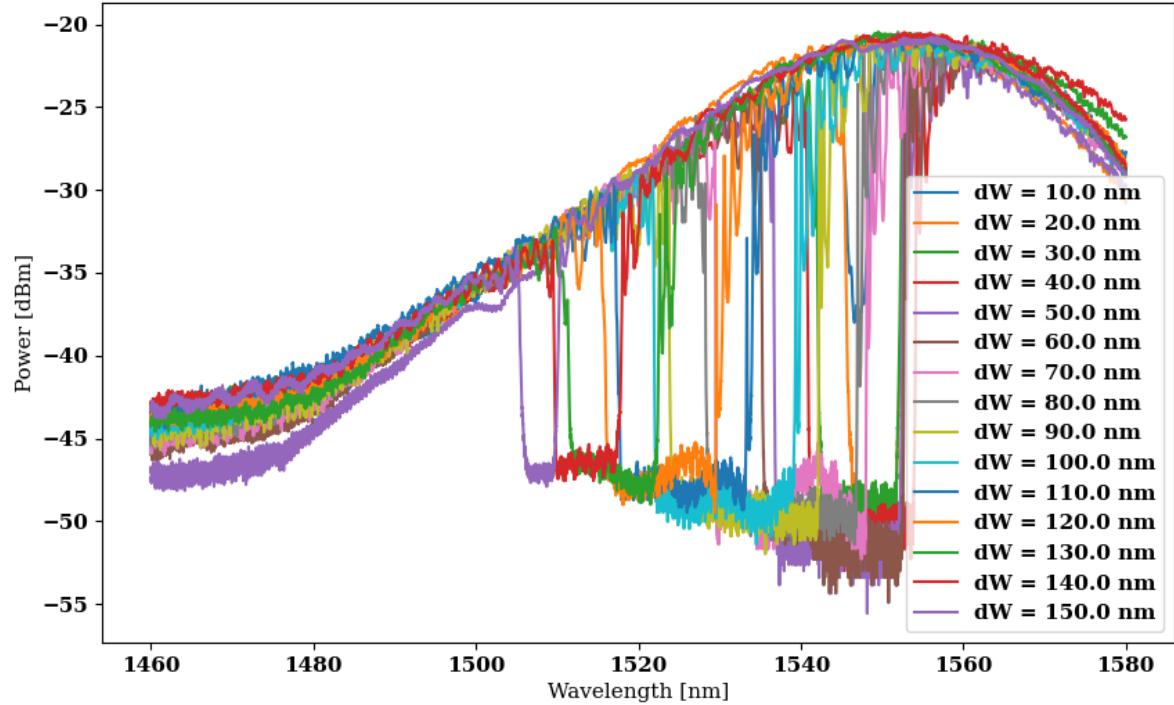
Extracted bandwidth and central wavelength of the Bragg gratings



Comparison of Bragg wavelength between simulation and experiment.



Raw measurement of all structures



Calibrated measurement of all structures (using envelope calibration)

